


FORM PTO-1449	Atty. Docket No.: 03-2477/L13.12-0258	Appl. No.: 10/817,419
<p>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</p> 	First Named Inventor:	
	Judy M. Gehman et al.	
	Filing Date	Group Art:
	April 1, 2004	

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
/JV/	AA	6,574,778	06/2003	Chang et al.	716	1
	AB	6,578,174	06/2003	Zizzo	716	1
	AC	6,536,028	03/2003	Katsioulas et al.	716	17
	AD	6,530,074	10/2002	Katsioulas et al.	716	17
	AE	6,366,874	04/2002	Lee et al.	703	14
/JV/	AF	6,334,207	12/2001	Joly et al.	716	17

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
AG						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

/JV/	AH	Sutherland, S.; "The IEEE Verilog 1364-2001 Standard What's New, and Why You Need It," 9th Annual International HDL Conference and Exhibition, March 2000. Pp. 1-8.
	AI	Cummings, C.; "Verilog-2001 Behavioral and Synthesis Enhancements," Revised April 2002, pp. 1-23.
	AJ	Cummings, C.; "New Verilog-2001 Techniques for Creating Parameterized Models (or Down with 'define and Death of a defparam!)" HDLCON 2002, pp. 1-10.
	AK	Wu, Y.; and MacDonald, P.; "Testing ASICs with Multiple Identical Cores," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 22, no. 3, March 2003, pp. 327-336.
	AJ	Miodrag Potkonjak et al. "Behavioral Synthesis of Area-Efficient Testable Designs Using Interaction Between Hardware Sharing and Partial Scan," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 14, no. 9, September 1995, pp. 1141-1154.
/JV/	AL	Chih-Chang Lin et al. "Test-Point Insertion: Scan Paths Through Functional Logic," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 17, no. 9, September 1998, pp. 838-851.

EXAMINER: /Jasjit Vidwan/	DATE CONSIDERED: 05/28/2007
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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AP						
AQ						
AR						

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	Document No.	Date	Country	Class	Sub Class	Translation Yes No
AS						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

/JV/	AT	Claus Schneider et al. "Modular Metrology Tools for Productivity Enhancement in Wafer Fabs," IEEE International Symposium on Semiconductor Manufacturing, Conference Proceedings, 1997. Oct. 6-8, 1997. Pp. B21-24.
/JV/	AU	Tianhao Zhang et al. "Design of Reconfigurable Composite Microsystems Based on Hardware/Software Codesign Principles," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, vol. 21, no. 8, Aug. 2002, pp. 987-995.
/JV/	AV	Ryota Kasai et al. "An Integrated Modular and Standard Cell VLSI Design Approach," IEEE Journal of Solid-State Circuits, vol. SC-20, no. 1, Feb. 1985 pp. 407-412.
/JV/	AW	Jeff Vanderlip. "LSI Logic Physical RTL Optimization (LSI PRO)," LSI Logic Corporation, Oct. 31, 2002. Pp. 1-7.
	AX	
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